

Abstract Submitted  
for the MAR14 Meeting of  
The American Physical Society

**Exciton dissociation at phthalocyanine-C<sub>60</sub> interfaces** S.W. ROBEY, G.J. DUTTON, NIST — Exciton dissociation and charge transfer processes occurring within 10's of nanometers of donor-acceptor interfaces are critical for the performance of organic photovoltaic (OPV) structures. We investigated fundamental issues of exciton dissociation near prototypical donor-acceptor interface using time-resolved two-photon photoemission (TR-2PPE). Phthalocyanine (Pc)-C<sub>60</sub> interfaces with known structures were formed using organic molecular beam epitaxy. Pc  $\pi \rightarrow \pi^*$  (Q-band) transitions were created by a sub-picosecond pump pulse, producing a population of singlet (S<sub>1</sub>) Pc excitons. The dynamics of this population were then probed via photoemission by a time-delayed UV pulse. For CuPc\C<sub>60</sub> interfaces, the dynamics for excitons created far from the interface were modeled with a combination of vibrational or intraband relaxation plus intersystem crossing (ISC) to triplet levels. Relaxation leads predominantly to triplet (T<sub>1</sub>) exciton levels on timescales of  $\approx$  1-2 ps. The decay dynamics of S<sub>1</sub> excitons excited in the CuPc layer adjacent to C<sub>60</sub> were increased due to the additional channel leading to exciton dissociation, occurring with a rate of  $\approx 7 \times 10^{12} \text{ sec}^{-1}$ . However, excitons that relax to T<sub>1</sub> levels at the interface dissociate with a rate  $\approx$  500 to 1000 times slower, providing a picture of the energy dependence of exciton dissociation at this interface. The dependence of exciton dissociation versus Pc thickness at analogous H<sub>2</sub>Pc \C<sub>60</sub> interfaces will also be presented. The results indicate that, for this interface, exciton dissociation is much faster for the interfacial layer with dissociation from the 2<sup>nd</sup>, and subsequent layers of H<sub>2</sub>Pc, reduced by at least a factor of 10.

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Date submitted: 14 Nov 2013

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